

ABSTRACT OF THE DISCLOSURE

BUILT-IN-SELF-TEST USING EMBEDDED MEMORY AND PROCESSOR IN AN
APPLICATION SPECIFIC INTEGRATED CIRCUIT

A test method for an ASIC uses an embedded processor in the ASIC to execute test routines from an embedded memory or an external memory. During ASIC production, the test routines can comprehensively test of the blocks of the ASIC without a complicated test pattern from test equipment. The test routines can also perform power-up tests in systems or end products containing the ASIC. Test selection, activation, and result output can be implement using a few terminals of the ASIC.

FIG. 1



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